

<b>Notice of References Cited</b>	Application/Control No. 10/699,135	Applicant(s)/Patent Under Reexamination TOHSCHÉ, ULF	
	Examiner Hiep Nguyen	Art Unit 2816	Page 1 of 1

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	C	US-6,720,813	04-2004	Yee et al.	327/218
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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